

09915854_CLS
Most Frequently Occurring Classifications of Patents Returned
From A Search of 09915854 on November 20, 2003

Original Classifications

4 714/724
3 250/310
3 714/719
3 714/733
2 714/731
2 714/736
2 714/738

Cross-Reference Classifications

3 714/724
3 714/736
2 324/73.1
2 326/16
2 365/201
2 714/733
2 714/734
2 714/735
2 714/738

Combined Classifications

7 714/724
5 714/733
5 714/736
4 250/310
4 714/738
3 324/73.1
3 365/201
3 714/719
3 714/734
2 250/492.2
2 326/16
2 714/726
2 714/731
2 714/735
2 714/739
2 714/744
2 716/17
2 716/4

09915854_CLSTITLES

Titles of Most Frequently Occurring Classifications of Patents Returned

From A Search of 09915854 on November 20, 2003

- 7 714/724 (4 OR, 3 XR)
 - Class 714 : ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
 - 714/699 PULSE OR DATA ERROR HANDLING
 - 714/724 .Digital logic testing
- 5 714/733 (3 OR, 2 XR)
 - Class 714 : ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
 - 714/699 PULSE OR DATA ERROR HANDLING
 - 714/724 .Digital logic testing
 - 714/733 ..Built-in testing circuit (BILBO)
- 5 714/736 (2 OR, 3 XR)
 - Class 714 : ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
 - 714/699 PULSE OR DATA ERROR HANDLING
 - 714/724 .Digital logic testing
 - 714/736 ..Device response compared to expected fault-free response
- 4 250/310 (3 OR, 1 XR)
 - Class 250 : RADIANT ENERGY
 - 250/306 INSPECTION OF SOLIDS OR LIQUIDS BY CHARGED PARTICLES
 - 250/310 .Electron probe type
- 4 714/738 (2 OR, 2 XR)
 - Class 714 : ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
 - 714/699 PULSE OR DATA ERROR HANDLING
 - 714/724 .Digital logic testing
 - 714/738 ..Including test pattern generator
- 3 324/73.1 (1 OR, 2 XR)
 - Class 324 : ELECTRICITY: MEASURING AND TESTING
 - 324/73.1 PLURAL, AUTOMATICALLY SEQUENTIAL TESTS
- 3 365/201 (1 OR, 2 XR)
 - Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL
 - 365/189.01 READ/WRITE CIRCUIT
 - 365/201 .Testing

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- 3 714/719 (3 OR, 0 XR)
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT
 DETECTION/RECOVERY
 714/699 PULSE OR DATA ERROR HANDLING
 714/718 .Memory testing
 714/719 ..Read-in with read-out and compare
- 3 714/734 (1 OR, 2 XR)
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT
 DETECTION/RECOVERY
 714/699 PULSE OR DATA ERROR HANDLING
 714/724 .Digital logic testing
 714/734 ..Structural (in-circuit test)
- 2 250/492.2 (1 OR, 1 XR)
 Class 250 : RADIANT ENERGY
 250/492.1 IRRADIATION OF OBJECTS OR MATERIAL
 250/492.2 .Irradiation of semiconductor devices
- 2 326/16 (0 OR, 2 XR)
 Class 326 : ELECTRONIC DIGITAL LOGIC CIRCUITRY
 326/16 WITH TEST FACILITATING FEATURE
- 2 714/726 (1 OR, 1 XR)
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT
 DETECTION/RECOVERY
 714/699 PULSE OR DATA ERROR HANDLING
 714/724 .Digital logic testing
 714/726 ..Scan path testing (e.g., level sensitive scan
 design (LSSD))
- 2 714/731 (2 OR, 0 XR)
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT
 DETECTION/RECOVERY
 714/699 PULSE OR DATA ERROR HANDLING
 714/724 .Digital logic testing
 714/726 ..Scan path testing (e.g., level sensitive scan
 design (LSSD))
 714/731 ...Clock or synchronization
- 2 714/735 (0 OR, 2 XR)
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT
 DETECTION/RECOVERY
 714/699 PULSE OR DATA ERROR HANDLING
 714/724 .Digital logic testing
 714/735 ..Device response compared to input pattern

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- 2 714/739 (1 OR, 1 XR)
 - Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
 - 714/699 PULSE OR DATA ERROR HANDLING
 - 714/724 .Digital logic testing
 - 714/738 ..Including test pattern generator
 - 714/739 ...Random pattern generation (includes
pseudorandom pattern)

- 2 714/744 (1 OR, 1 XR)
 - Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
 - 714/699 PULSE OR DATA ERROR HANDLING
 - 714/724 .Digital logic testing
 - 714/738 ..Including test pattern generator
 - 714/744 ...Clock or synchronization

- 2 716/17 (1 OR, 1 XR)
 - Class 716 : DATA PROCESSING: DESIGN AND ANALYSIS OF
CIRCUIT OR SEMICONDUCTOR MASK
 - 716/1 CIRCUIT DESIGN
 - 716/17 .Programmable integrated circuit (e.g., basic
cell, standard cell, macrocell)

- 2 716/4 (1 OR, 1 XR)
 - Class 716 : DATA PROCESSING: DESIGN AND ANALYSIS OF
CIRCUIT OR SEMICONDUCTOR MASK
 - 716/1 CIRCUIT DESIGN
 - 716/4 .Testing or evaluating

09915854_LIST

PLUS Search Results for S/N 09915854, Searched November 20, 2003

5499249
4423509
4967151
4571679
4853928
4875209
5253181
5323400
5627841
5850512
6000040
6130428
6167542
6211517
6211517
5436912
4414669
4625310
4811343
4951220
5278841
5357471
5404359
5600658
4308616
4896322
5550839
5748638
5944846
4267463
4293950
4371952
4387304
4546473
4575718
4594704
4764926
4772845
4858156
5177318
5297151
5377203
5550844
5602856
5744946
5844916

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5872795
5898705
5930814
5974579